



## Electrical Characteristics $T_J = 25^\circ\text{C}$ unless otherwise noted

Symbol	Parameter	Test Conditions	Min	Typ	Max	Units
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### Off Characteristics

$BV_{DSS}$	Drain to Source Breakdown Voltage	$I_D = 250\mu\text{A}, V_{GS} = 0\text{V}$	30			V
$\frac{\Delta BV_{DSS}}{\Delta T_J}$	Breakdown Voltage Temperature Coefficient	$I_D = 250\mu\text{A}$ , referenced to $25^\circ\text{C}$		29		mV/ $^\circ\text{C}$
$I_{DSS}$	Zero Gate Voltage Drain Current	$V_{DS} = 24\text{V}, V_{GS} = 0\text{V}$			1	$\mu\text{A}$
$I_{GSS}$	Gate to Source Leakage Current	$V_{GS} = \pm 20\text{V}, V_{DS} = 0\text{V}$			$\pm 100$	nA

### On Characteristics

$V_{GS(th)}$	Gate to Source Threshold Voltage	$V_{GS} = V_{DS}, I_D = 250\mu\text{A}$	1	1.6	3	V
$\frac{\Delta V_{GS(th)}}{\Delta T_J}$	Gate to Source Threshold Voltage Temperature Coefficient	$I_D = 250\mu\text{A}$ , referenced to $25^\circ\text{C}$		-4		mV/ $^\circ\text{C}$
$r_{DS(on)}$	Static Drain to Source On Resistance	$V_{GS} = 10\text{V}, I_D = 30\text{A}$		1.3	1.8	m $\Omega$
		$V_{GS} = 4.5\text{V}, I_D = 25\text{A}$		1.9	2.6	
		$V_{GS} = 10\text{V}, I_D = 30\text{A}, T_J = 125^\circ\text{C}$		1.5	2.2	
$g_{FS}$	Forward Transconductance	$V_{DD} = 10\text{V}, I_D = 30\text{A}$		180		S

### Dynamic Characteristics

$C_{iss}$	Input Capacitance	$V_{DS} = 15\text{V}, V_{GS} = 0\text{V}, f = 1\text{MHz}$		4436	5900	pF
$C_{oss}$	Output Capacitance			2360	3140	pF
$C_{rss}$	Reverse Transfer Capacitance			320	480	pF
$R_g$	Gate Resistance	$f = 1\text{MHz}$		1		$\Omega$

### Switching Characteristics

$t_{d(on)}$	Turn-On Delay Time	$V_{DD} = 15\text{V}, I_D = 1\text{A}, V_{GS} = 10\text{V}, R_{GEN} = 6\Omega$		19	34	ns
$t_r$	Rise Time			12	22	ns
$t_{d(off)}$	Turn-Off Delay Time			68	109	ns
$t_f$	Fall Time			100	160	ns
$Q_g$	Total Gate Charge		$V_{GS} = 10\text{V}, V_{DD} = 15\text{V}, I_D = 30\text{A}$		70	98
$Q_{gs}$	Gate to Source Charge			12		nC
$Q_{gd}$	Gate to Drain "Miller" Charge			10		nC

### Drain-Source Diode Characteristics

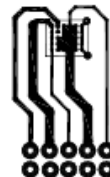
$V_{SD}$	Source to Drain Diode Forward Voltage	$V_{GS} = 0\text{V}, I_S = 2.2\text{A}$ (Note 2)		0.7	1.2	V
$t_{rr}$	Reverse Recovery Time	$I_F = 30\text{A}, di/dt = 100\text{A}/\mu\text{s}$		57	91	ns
$Q_{rr}$	Reverse Recovery Charge			108	173	nC

#### NOTES:

1.  $R_{\theta JA}$  is determined with the device mounted on a 1in<sup>2</sup> pad 2 oz copper pad on a 1.5 x 1.5 in. board of FR-4 material.  $R_{\theta JC}$  is guaranteed by design while  $R_{\theta CA}$  is determined by the user's board design.



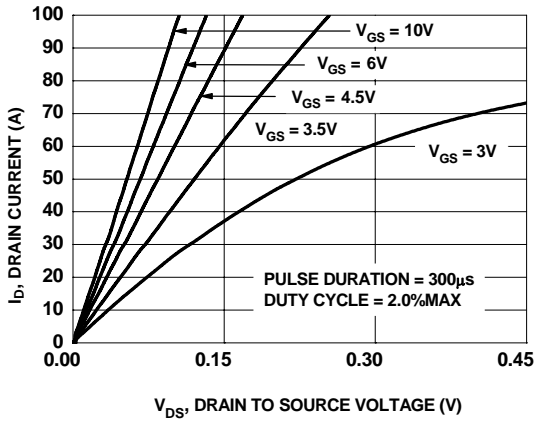
a.  $46^\circ\text{C}/\text{W}$  when mounted on a 1 in<sup>2</sup> pad of 2 oz copper.



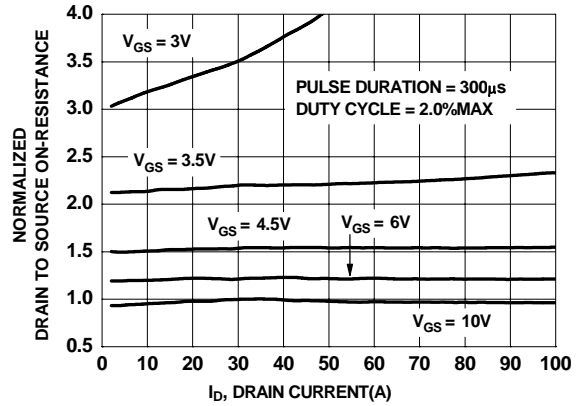
b.  $98^\circ\text{C}/\text{W}$  when mounted on a minimum pad of 2 oz copper.

2. Pulse Test: Pulse Width < 300 $\mu\text{s}$ , Duty cycle < 2.0%.

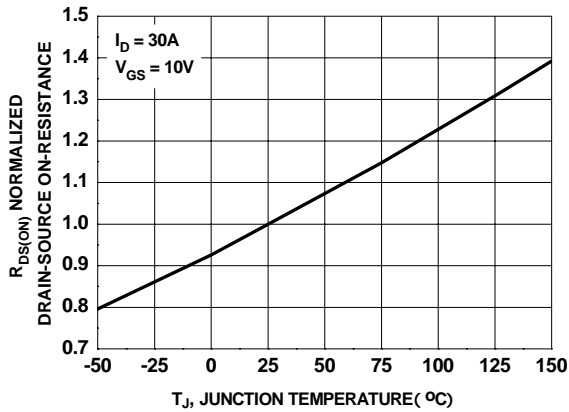
**Typical Characteristics**  $T_J = 25^\circ\text{C}$  unless otherwise noted



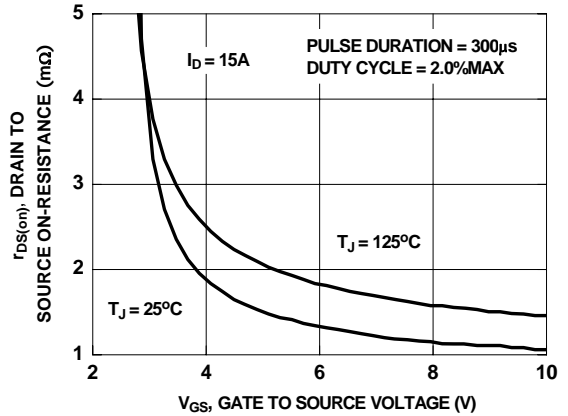
**Figure 1. On-Region Characteristics**



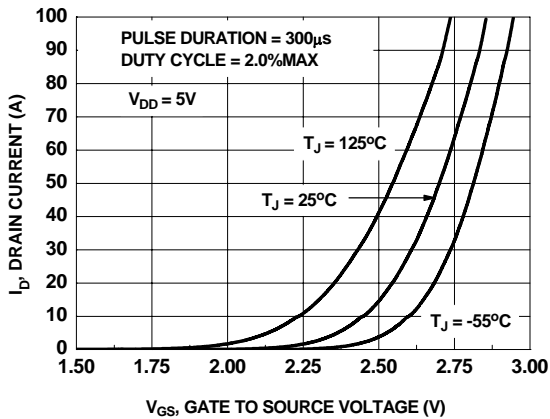
**Figure 2. Normalized On-Resistance vs Drain Current and Gate Voltage**



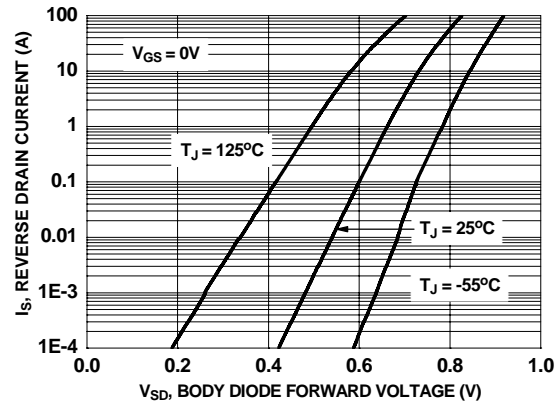
**Figure 3. Normalized On-Resistance vs Junction Temperature**



**Figure 4. On-Resistance vs Gate to Source Voltage**

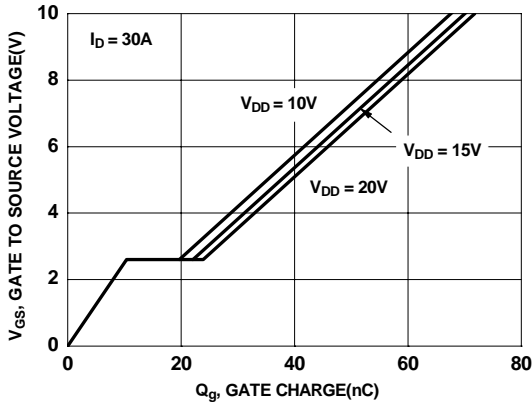


**Figure 5. Transfer Characteristics**

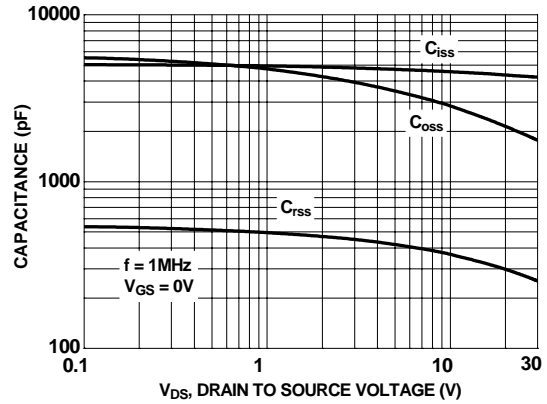


**Figure 6. Source to Drain Diode Forward Voltage vs Source Current**

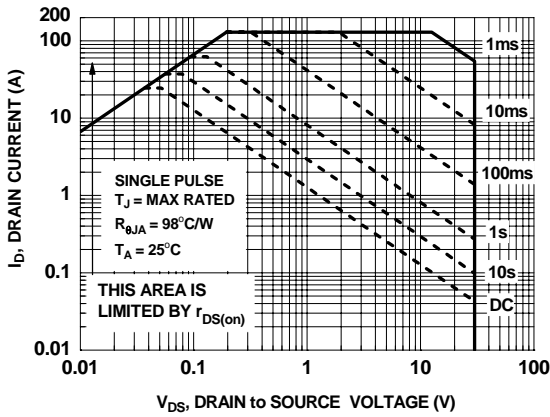
**Typical Characteristics**  $T_J = 25^\circ\text{C}$  unless otherwise noted



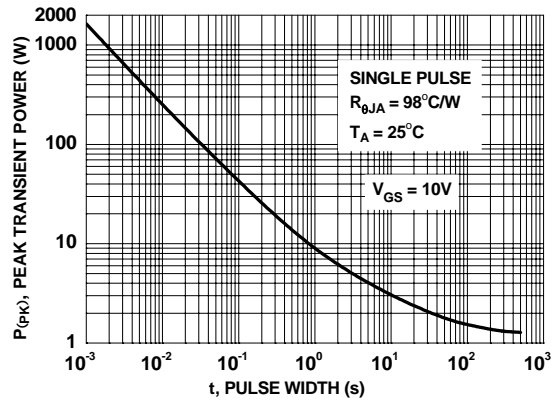
**Figure 7. Gate Charge Characteristics**



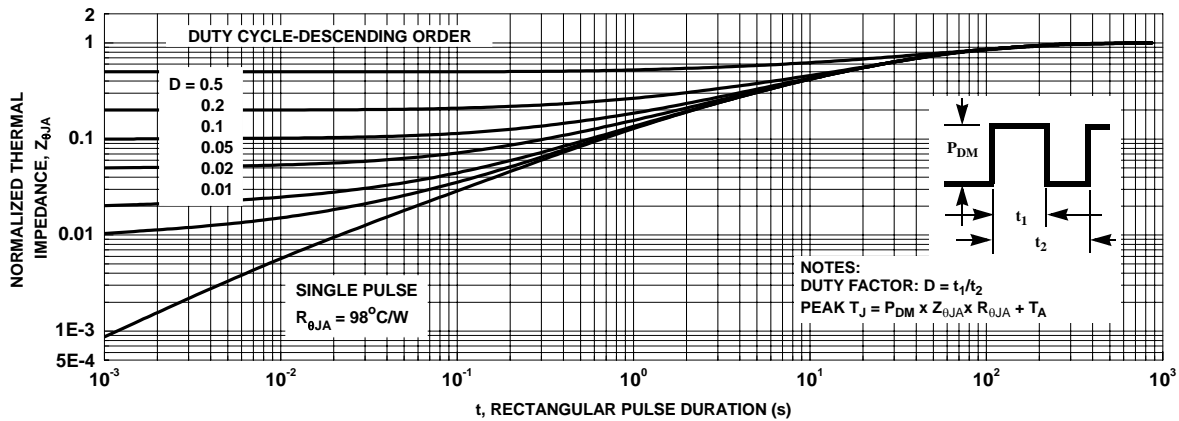
**Figure 8. Capacitance vs Drain to Source Voltage**



**Figure 9. Forward Bias Safe Operating Area**

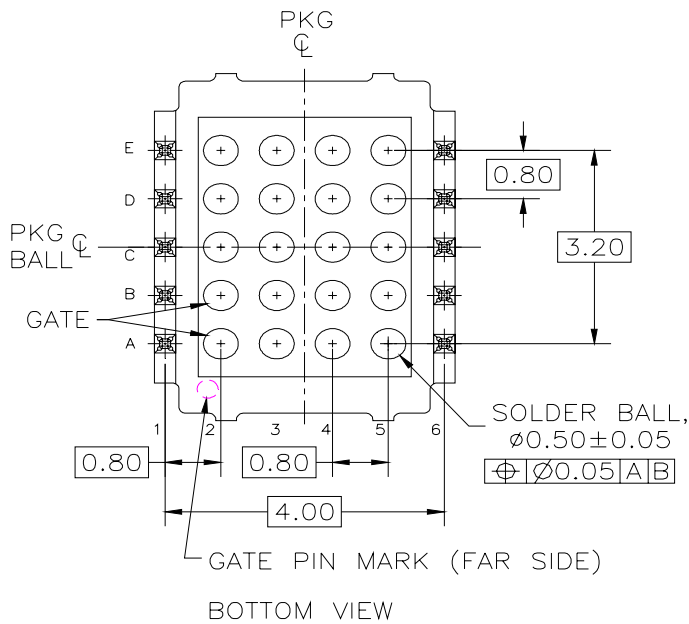
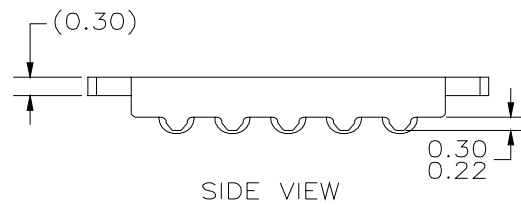
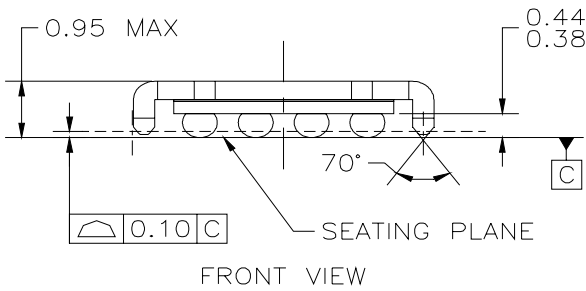
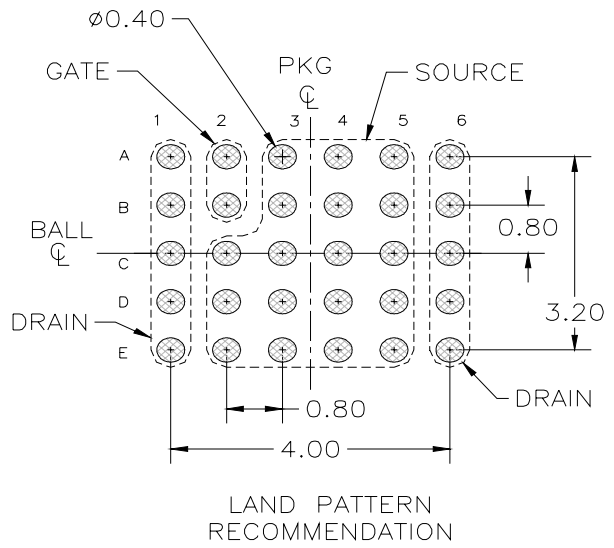
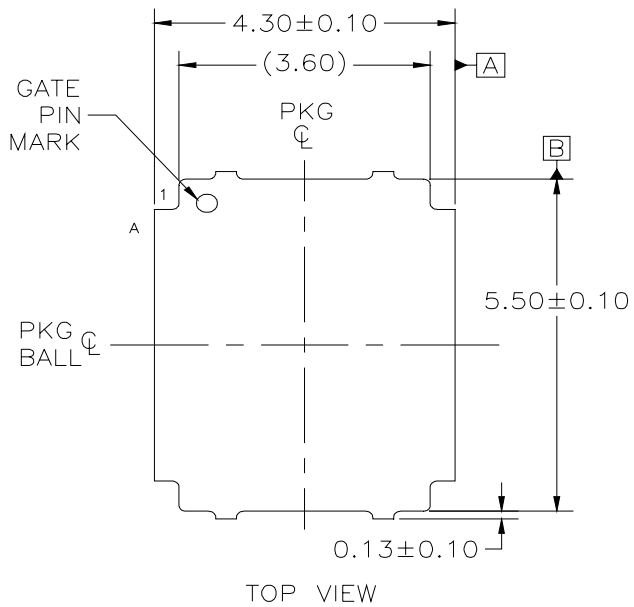


**Figure 10. Single Pulse Maximum Power Dissipation**



**Figure 11. Transient Thermal Response Curve**

### Dimensional Outline and Pad Layout



- NOTES: UNLESS OTHERWISE SPECIFIED  
 A) ALL DIMENSIONS ARE IN MILLIMETERS.  
 B) NO JEDEC REGISTRATION REFERENCE AS OF MARCH 2006.  
 C) TERMINAL CONFIGURATION TABLE


POSITION	DESIGNATION	TYPE
A1,B1,C1,D1,E1, A6,B6,C6,D6,E6	DRAIN	COPPER STUD
A2,B2	GATE	SOLDER BALL
A3,A4,A5,B3,B4, B5,C2,C3,C4,C5, D2,D3,D4,D5, E2,E3,E4,E5	SOURCE	

BGA020DREVB



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